gent experience

Inventor Information

Inventor One Given Name:: Family Name::

City of Residence:: Country of Residence:: Citizenship Country:: Inventor Two Given Name::

Family Name::

City of Residence:: Country of Residence:: Citizenship Country::

Inventor Three Given Name:: Family Name::

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Application Information

Title Line One::
Title Line Two::

Total Drawing Sheets::

Docket Number::

METHOD AND APPARATUS FOR ION

ATTACHMENT MASS SPECTROMETRY

10

109675

Prior Foreign Applications

Foreign Application One:: 2000-169644

Filing Date::

Country:: Priority Claimed:: June 6, 2000

JAPAN YES

Assignee Information

Name of assignee::

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JAPAN